

**Notice of References Cited**

Application/Control No.

09/653,156

Applicant(s)/Patent Under  
Reexamination  
AGARWAL ET AL.

Examiner

Yennhu B Huynh

Art Unit

2813

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6274428B1	08-2002	Wu	438/255
X	B	US-6291289B2	09-2002	Rhodes et al.	438/239
X	C	US-6174770B1	01-2002	Chi	438/255
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	K	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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